

Notice of References Cited	Application/Control No. 10/600,738		Applicant(s)/Patent Under Reexamination SMITH ET AL.	
	Examiner Paula W. Klimach		Art Unit 2135	Page 1 of 1

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*	B	US-6,523,166	02-2003	Mishra et al.	717/174
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.